## Notice of References Cited Application/Control No. 10/593,848 Examiner OOMMEN JACOB Applicant(s)/Patent Under Reexamination LEE ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2001/0038479	11-2001	Liu et al.	359/127
	В	US-			
	O	US-			
	D	US-			
	Е	US-			
	F	US-			
	G	US-			
	Ι	US-		1	
	Ι	US-	6		
	J	US-			
	K	US-	<b>1</b>		
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 03055111 A1	07-2003	World Intellect	HIIRONEN O et al.	
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	s					
	-			2-12-3-6	100	

## NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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